

Notice of References Cited	Application/Control No. 10/067,140	Applicant(s)/Patent Under Reexamination TSIKOS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0218070	11-2003	Tsikos et al.	235/472.01
	B	US-2003/0189098	10-2003	Tsikos et al.	235/454
	C	US-2003/0150917	08-2003	Tsikos et al.	235/454
	D	US-2003/0150916	08-2003	Tsikos et al.	235/454
	E	US-2003/0146282	08-2003	Tsikos et al.	235/454
	F	US-2003/0102379	06-2003	Tsikos et al.	235/462.45
	G	US-2003/0098349	05-2003	Tsikos et al.	235/462.01
	H	US-2003/0094495	05-2003	Knowles et al.	235/462.14
	I	US-2003/0089778	05-2003	Tsikos et al.	235/454
	J	US-2003/0085281	05-2003	Knowles et al.	235/454
	K	US-2003/0085280	05-2003	Tsikos et al.	235/454
	L	US-2003/0080192	05-2003	Tsikos et al.	235/462.14
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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